

Notice of References Cited	Application/Control No. 10/659,066	Applicant(s)/Patent Under Reexamination CALDER ET AL.	
	Examiner MARY STEELMAN	Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,317,741 A	05-1994	Schwanke, Robert W.	717/120
*	B	US-5,428,788 A	06-1995	Schwanke, Robert W.	717/120
*	C	US-6,226,789 B1	05-2001	Tye et al.	717/138
*	D	US-6,526,405 B1	02-2003	Mannila et al.	707/6
*	E	US-6,802,046 B2	10-2004	Coelho et al.	716/4
*	F	US-7,065,544 B2	06-2006	Moreno, Pedro J.	708/422
*	G	US-7,158,961 B1	01-2007	Charikar, Moses Samson	707/2
*	H	US-2003/0189904 A1	10-2003	Li, Jonathan Q.	370/252
*	I	US-2005/0120333 A1	06-2005	Inoue et al.	717/120
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Merriam-Webster's Collegiate Dictionary Tenth Edition, p. 59 (2001), definition of arbitrary.
	V	Gitchell, David; Tran, Nicholas, "SIM: A Utility for Detecting Similarity in Computer Programs", 1999 ACM, p. 266-270, retrieved from ACM 09/12/2007.
	W	Podgurski, Andy; Yang, Charles; "Partition Testing, Stratified Sampling, and Cluster Analysis", 1993 ACM, p. 169-181, retrieved from ACM 09/12/2007.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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